

FH1704GS6

N-Channel Enhancement Mode Power MOSFET

Description:

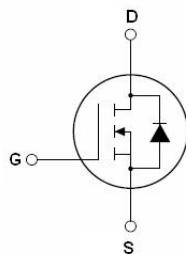
This N channel SGT MOSFET has been designed to very low on-state resistance ($R_{DS(on)}$) and yet maintain superior switching performance, especially for high efficiency power management applications

Applications:

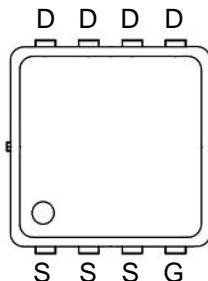
- DC-DC Converter
- Power Tools
- Load Switching

Features:

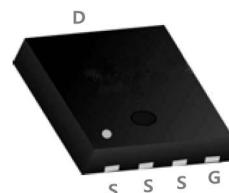
- $V_{DS} = 40V, I_D = 74A$
- $R_{DS(on)}(\text{Typ.}) = 2.8m\Omega @ V_{GS} = 10V$
- $R_{DS(on)}(\text{Typ.}) = 4.4m\Omega @ V_{GS} = 4.5V$
- High density cell design for ultra low Rdson
- Excellent package for good heat dissipation
- FastSwitching



Schematic dia gram



Marking and pin Assignment



PDFN3.3x3.3-8L top and bottom view

Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

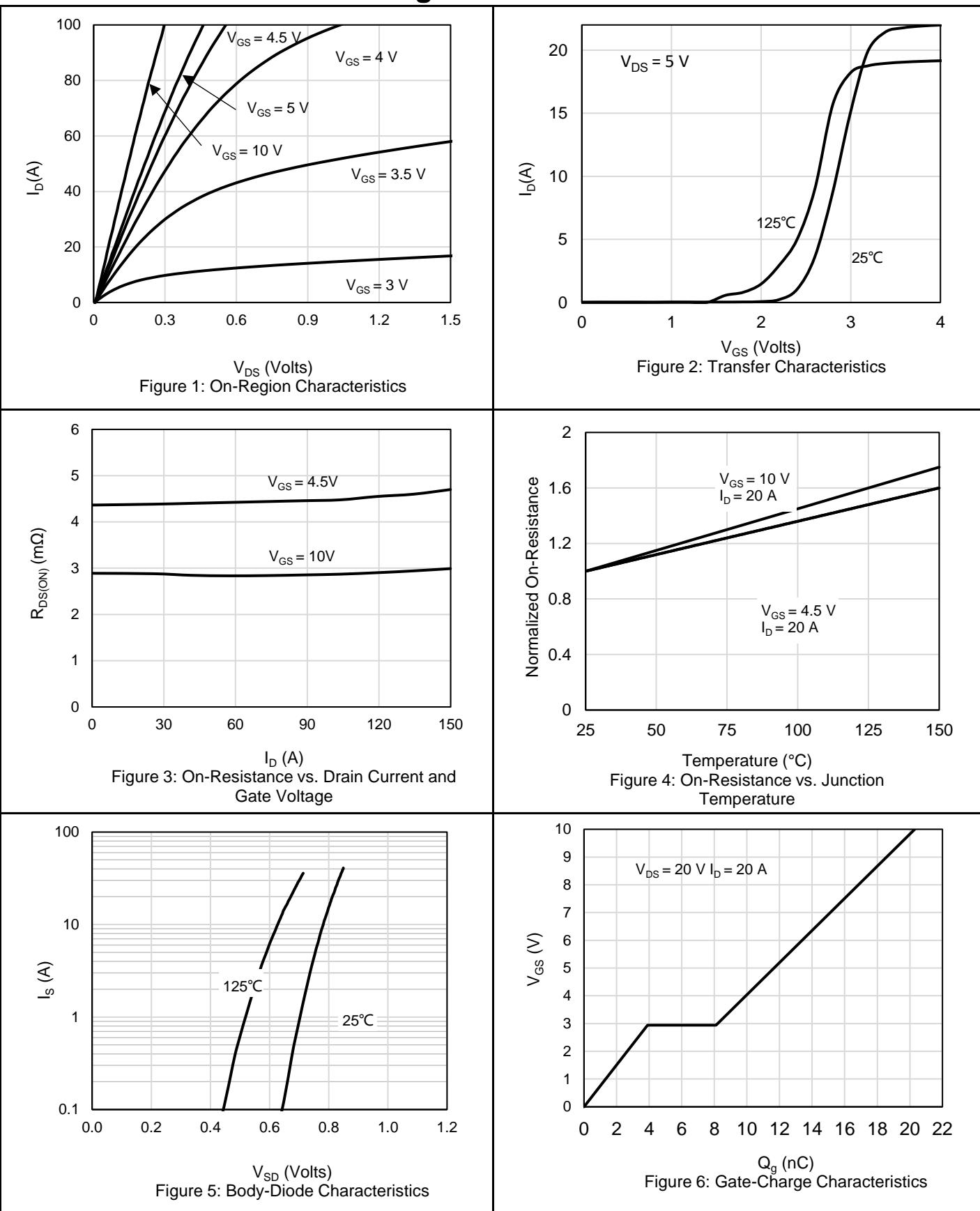
Symbol	Parameter	Value	Units
V_{DS}	Drain-Source Voltage	40	V
I_D	Drain Current - Continuous ($T_C = 25^\circ C$) ^(Note 1)	74	A
	Drain Current - Continuous ($T_C = 100^\circ C$)	52	A
I_{DM}	Drain Current - Pulsed ^(Note 2)	222	A
V_{GS}	Gate-Source Voltage	± 20	V
E_{AS}	Single Pulsed Avalanche Energy ^(Note 3)	76	mJ
P_D	Power Dissipation ($T_C = 25^\circ C$)	40	W
T_J, T_{STG}	Operating and Storage Temperature Range	-55 to +150	$^\circ C$
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Steady-State	3.1	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient Steady-State ^(Note 4)	58	$^\circ C/W$

Notes:

1. The max drain current rating is package limited
2. Repetitive Rating: Pulse width limited by maximum junction temperature
3. $L = 0.5 \text{ mH}, V_{DD} = 20V, I_{AS} = 17.5 \text{ A}, R_G = 50 \Omega, \text{Starting } T_J = 25^\circ C$
4. Mount on minimum PCB layout

Electrical Characteristics		$(T_J = 25^\circ C$ unless otherwise noted)				
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_D = 250 \mu A$	40			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 40 V, V_{GS} = 0 V,$			1	μA
		$V_{DS} = 40 V, V_{GS} = 0 V,$ $T_J = 150^\circ C$			100	
I_{GSS}	Gate Leakage Current	$V_{GS} = \pm 20 V, V_{DS} = 0 V$			± 100	nA
$V_{GS(TH)}$	Gate Threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.5	2.5	V
$R_{DS(ON)}$	Drain-Source on-state resistance	$V_{GS} = 10 V, I_D = 20 A$		2.8	3.5	$m\Omega$
		$V_{GS} = 4.5 V, I_D = 15 A$		4.4	6.2	
Dynamic Characteristics						
C_{ISS}	Input Capacitance	$V_{DS} = 20 V, V_{GS} = 0 V,$ $F = 1 MHz$		1193		pF
C_{OSS}	Output Capacitance			426		pF
C_{RSS}	Reverse Transfer Capacitance			30		pF
R_G	Gate Resistance	$F = 1 MHz$		8.4		Ω
Switching Characteristics						
$T_{D(ON)}$	Turn On Delay Time	$V_{DD} = 20 V, I_D = 20 A,$ $V_{GS} = 10 V, R_G = 6 \Omega$		7		nS
T_R	Rise Time			6.5		nS
$T_{D(OFF)}$	Turn Off Delay Time			29		nS
T_F	Fall Time			13		nS
Q_G	Total Gate Charge	$V_{DD} = 20 V, I_D = 20 A,$ $V_{GS} = 10 V$		20.3		nC
Q_{GS}	Gate-Source Charge			3.9		nC
Q_{GD}	Gate-Drain Charge			4.2		nC
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Body-Diode Forward Current			74		A
I_{SM}	Maximum Pulsed Body-Diode Forward Current ^(NOTE 2)			222		A
V_{SD}	Diode Forward Voltage	$V_{GS} = 0 V, I_S = 1 A$		0.7	1	V
T_{RR}	Reverse recovery time	$V_{DD} = 20 V, I_D = 15 A,$ $di/dt = 100 A/\mu s$		30		ns
Q_{RR}	Reverse recovery charge			17		nC

Electrical Characteristics Diagrams



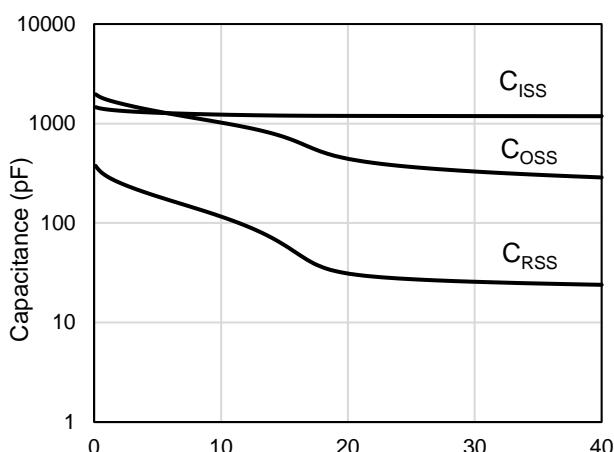


Figure 7: Capacitance Characteristics

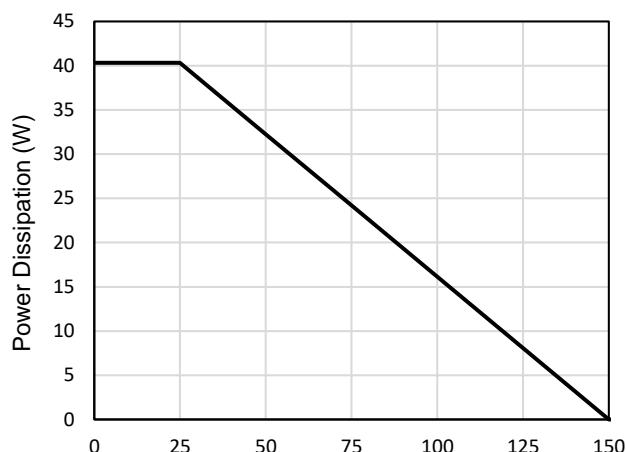


Figure 8: Power De-rating

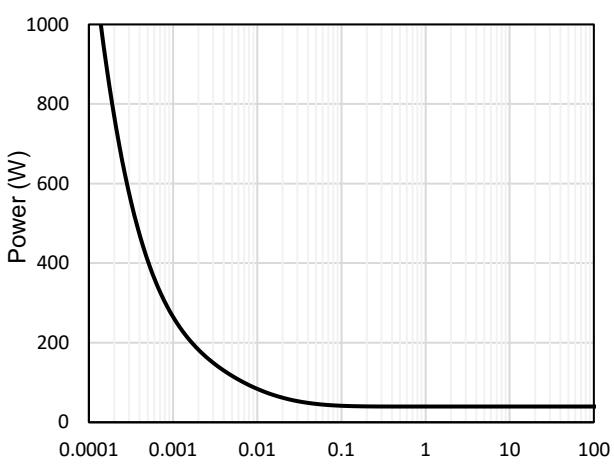


Figure 9: Single Pulse Power Rating Junction-to-Case

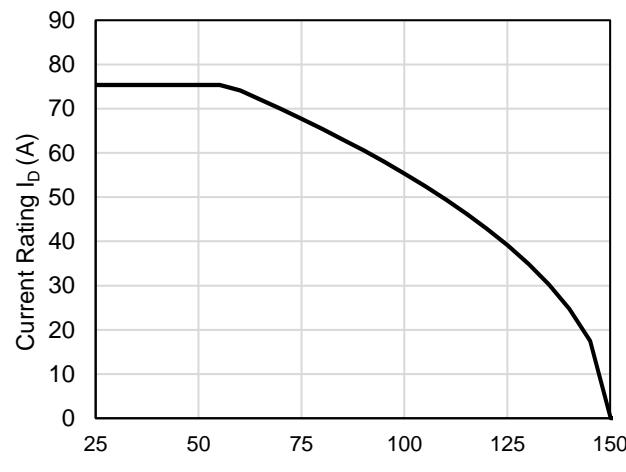


Figure 10: Current De-rating

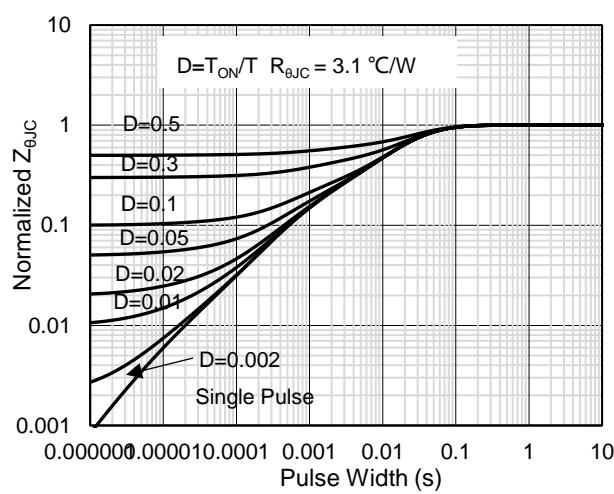


Figure 11: Normalized Maximum Transient Thermal Impedance

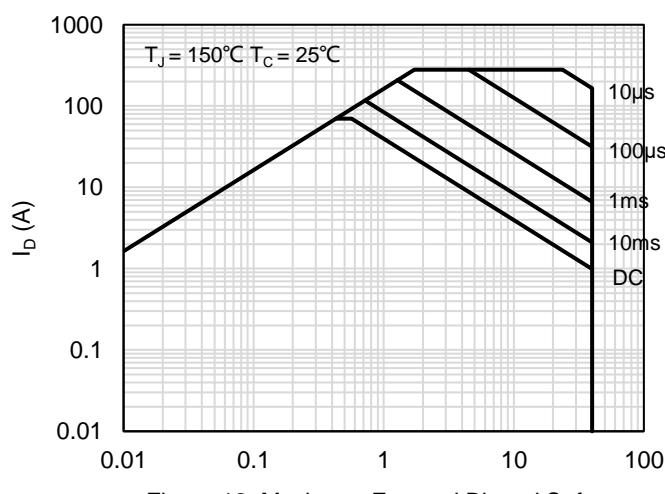
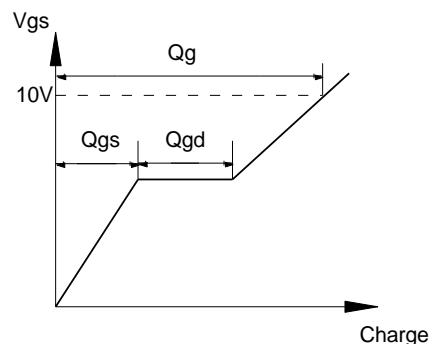
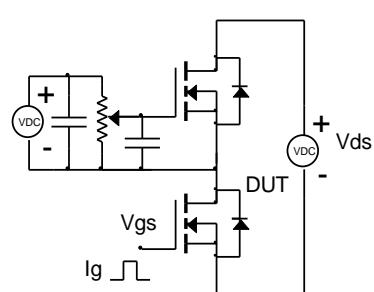


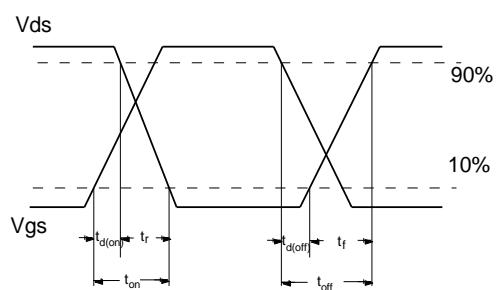
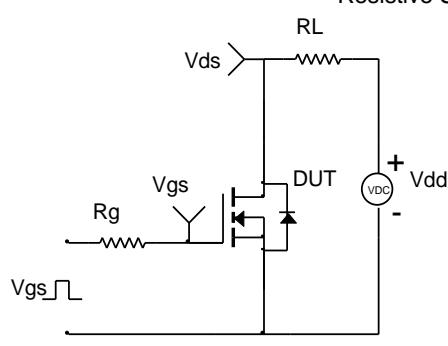
Figure 12: Maximum Forward Biased Safe Operating Area

Test Circuit and Waveform

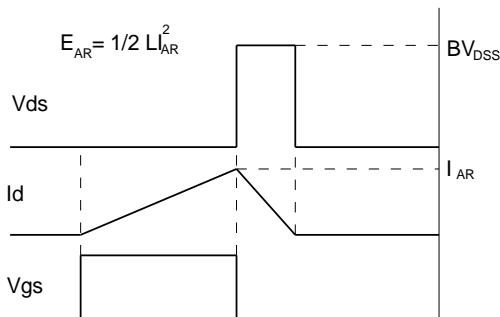
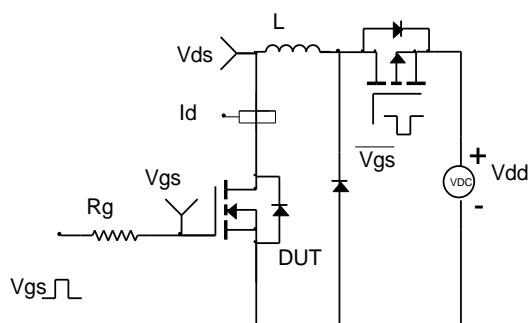
Gate Charge Test Circuit & Waveform



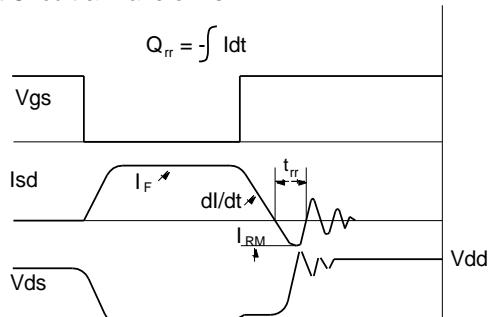
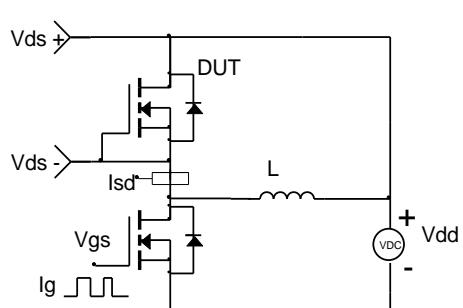
Resistive Switching Test Circuit & Waveforms



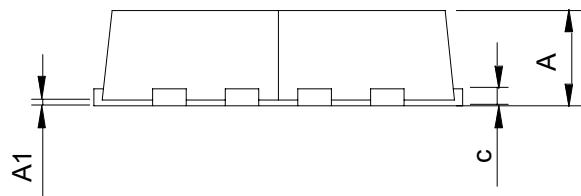
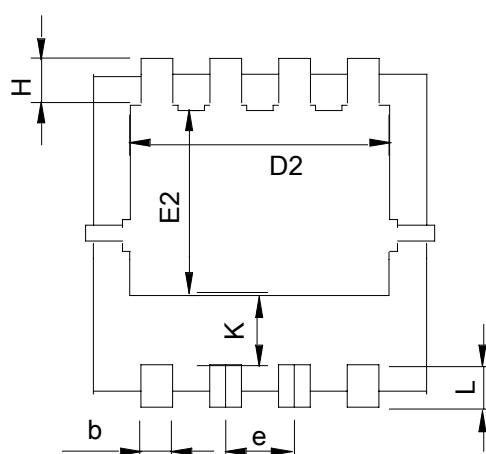
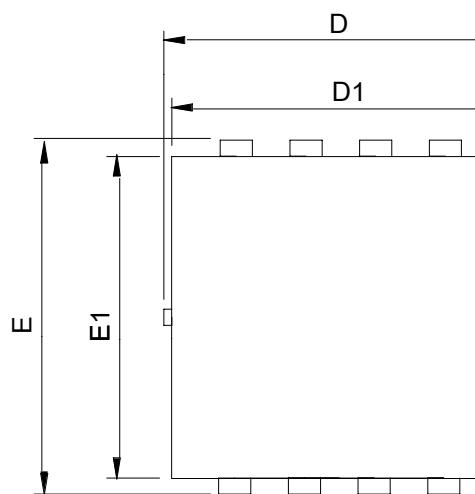
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



Package Information : PDFN3.3x3.3-8L



SYMBOL	PDFN3.3x3.3-8L			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	0.70	1.00	0.028	0.039
A1	0.00	0.05	0.000	0.002
b	0.25	0.35	0.010	0.014
c	0.14	0.20	0.006	0.008
D	3.10	3.50	0.122	0.138
D1	3.05	3.25	0.120	0.128
D2	2.35	2.55	0.093	0.100
E	3.10	3.50	0.122	0.138
E1	2.90	3.10	0.114	0.122
E2	1.64	1.84	0.065	0.072
e	0.65 BSC		0.026 BSC	
H	0.32	0.52	0.013	0.020
K	0.59	0.79	0.023	0.031
L	0.25	0.55	0.010	0.022